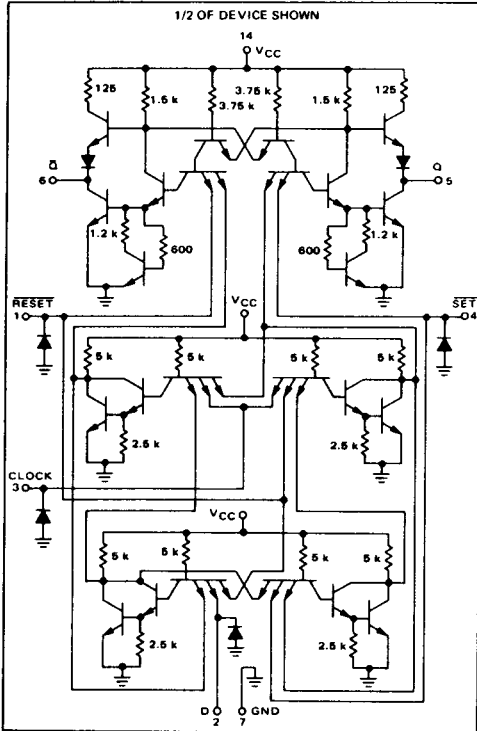


4-10

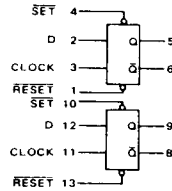
DUAL TYPE D FLIP-FLOP

MTTL MC7400P series
MTTL MC5400L/7400L series

MC5479L*
MC7479P,L*



This dual type D flip flop triggers on the positive edge of the clock input. During the clock transition the state of the D input is transferred to the Q output. The device is useful in shift registers and simple counters.



t_n	t_{n+1}	\bar{Q}
0	0	1
1	1	0

Input Loading Factor:

- D = 1
- SET, CLOCK = 2
- RESET = 3

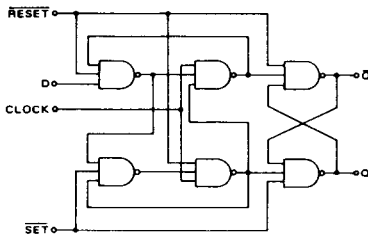
Output Loading Factor = 10

Total Power Dissipation = 84 mW typ/pkg

Propagation Delay Time = 16 ns typ

Operating Frequency = 30 MHz typ

* L suffix = TO-116 ceramic package (Case 632)
P suffix = TO-116 plastic package (Case 606)
See General Information section for package outline dimensions.



LOGIC DIAGRAM
1/2 OF DEVICE SHOWN

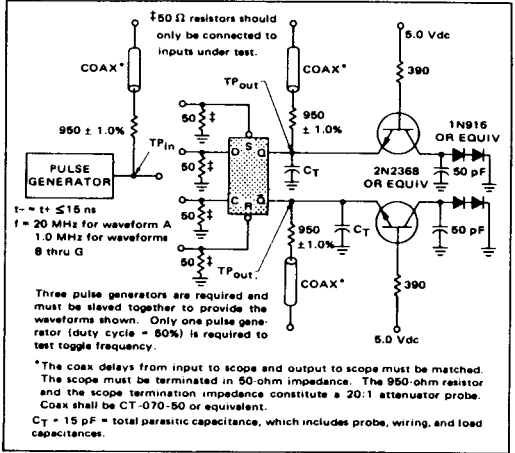
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OPERATING CHARACTERISTICS

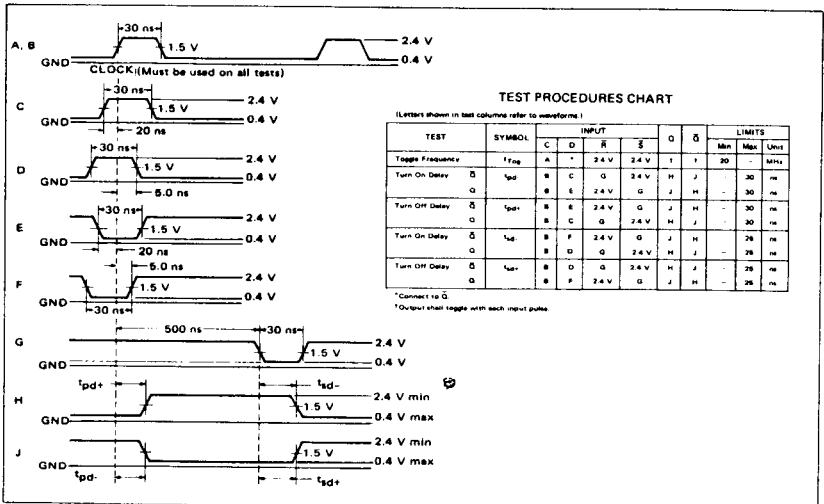
Data may be applied to the D input any time following 5.0 ns after the leading edge of a clock pulse and 20 ns before the leading edge of the following clock pulse. The state of the D input when the clock changes from the positive logic "0" state to the positive logic "1" state is transferred to the Q output of the flip-flop. The data input cannot be changed between the setup time (20 ns) and the hold time (5.0 ns) without adversely affecting the operation of the flip-flop.

The direct SET and RESET inputs override the clock, and may be applied any time during the operating cycle.

SWITCHING TIME TEST CIRCUIT



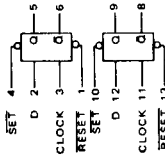
VOLTAGE WAVEFORMS AND DEFINITIONS



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ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one flip-flop. The other flip-flop is tested in the same manner.



Characteristic		Pin Under Test		TEST CURRENT/VOLTAGE VALUES (All Temperatures)												Gnd								
				Volts																				
				I_{OL}	I_{OH}	V_{IL}	V_{IH}	V_{MH}	V_{RH}	V_{H1}	V_{H0}	V_{CC}	V_{CCL}	V_{CCH}	V_{CCH}									
Input				MC5479 Test Limits				MC7479 Test Limits				TEST CURRENT/VOLTAGE APPLIED TO PINS LISTED BELOW:												
Forward Current				Min	Max	Unit	Min	Max	Unit	I_{OL}	I_{OH}	V_{IL}	V_{IH}	V_{MH}	V_{RH}	V_{H1}	V_{H0}	V_{CC}	V_{CCL}	V_{CCH}	V_{CCH}			
Set				-1.6	mAdc		-1.6	mAdc		-	-	2	-	-	1.4	-	-	-	-	-	14	3.7,11		
Reset				-3.2	mAdc		-3.2	mAdc		-	-	1	-	-	1	-	-	-	-	-	-	14	2.3,7,11	
Clock				-3.2	mAdc		-3.2	mAdc		-	-	3	-	-	1	-	-	-	-	-	-	14	3.7,11	
Leakage Current				Min	Max	Unit	Min	Max	Unit	I_{R1}	I_{R2}	V_{IL}	V_{IH}	V_{MH}	V_{RH}	V_{H1}	V_{H0}	V_{CC}	V_{CCL}	V_{CCH}	V_{CCH}			
Set				40	μ Adc		40	μ Adc		-	-	-	-	-	3.4	-	-	-	-	-	-	-	1.7,11	
Reset				80	μ Adc		80	μ Adc		-	-	-	-	4	1.2,3*	-	-	-	-	-	-	-	7,11	
Clock				120	μ Adc		120	μ Adc		-	-	-	-	1	3*,4	-	-	-	-	-	-	-	2,7,11	
Set				80	μ Adc		80	μ Adc		-	-	-	-	3	4	-	-	-	-	-	-	-	1.2,7,11	
Reset				1.0	mAdc		1.0	mAdc		-	-	-	-	2	3.4	-	-	-	-	-	-	-	1.7,11	
Clock				-			-			-	-	-	-	4	1.2,3*	-	-	-	-	-	-	-	7,11	
Set				-			-			-	-	-	-	1	3*,4	-	-	-	-	-	-	-	2,7,11	
Clock				-			-			-	-	-	-	3	4	-	-	-	-	-	-	-	1.2,7,11	
Output				MC5479 Test Limits				MC7479 Test Limits				TEST CURRENT/VOLTAGE APPLIED TO PINS LISTED BELOW:												
Output Voltage				Min	Max	Unit	Min	Max	Unit	V_{OL}	V_{OH}	V_{IL}	V_{IH}	V_{MH}	V_{RH}	V_{H1}	V_{H0}	V_{CC}	V_{CCL}	V_{CCH}	V_{CCH}			
Set				0.4	Vdc		0.4	Vdc		5	-	-	-	-	-	4	1	14	14	14	14	2.3,7,11		
Reset				0.4	Vdc		0.4	Vdc		6	-	-	-	-	-	1	4	14	14	14	14	2.3,7,11		
Clock				2.4	Vdc		2.4	Vdc		-	5	-	-	-	-	1	4	14	14	14	14	2.3,7,11		
Set				2.4	Vdc		2.4	Vdc		-	6	-	-	-	-	1	4	14	14	14	14	2.3,7,11		
Reset				-20	mAdc		-20	mAdc		-	-	-	-	-	-	-	-	-	-	-	-	-	4.5,7,11	
Clock				-57	mAdc		-57	mAdc		-	-	-	-	-	-	-	-	-	-	-	-	-	1.6,7,11	
Power Requirements				MC5479 Test Limits				MC7479 Test Limits				TEST CURRENT/VOLTAGE APPLIED TO PINS LISTED BELOW:												
Total Device				Min	Max	Unit	Min	Max	Unit	I_{SC}	I_{PD}	V_{IL}	V_{IH}	V_{MH}	V_{RH}	V_{H1}	V_{H0}	V_{CC}	V_{CCL}	V_{CCH}	V_{CCH}			
Power Supply Drain				28.8	mAdc		28.8	mAdc		-	-	-	-	-	-	-	-	-	-	-	-	-	2.3,4,7,10,11,12	
Power Supply Drain				28.8	mAdc		28.8	mAdc		-	-	-	-	-	-	-	-	-	-	-	-	-	-	1.2,3,7,11,12,13

*Momentarily ground pin prior to taking measurement, then set to state indicated.